


<b>Search Notes</b>  	<b>Application/Control No.</b>  10562371	<b>Applicant(s)/Patent Under Reexamination</b>  HASTWELL ET AL.
	<b>Examiner</b>  STEPHANIE K MUMMERT	<b>Art Unit</b>  1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
inventor name search - PALM	5/30/08	SKM
searched STN - medline, caplus, biosis - deposition, nano, micro, electrostatic, patterning	6/21/08	SKM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner